## Search Notes



App	olicat	ion/	Con	trol	No

10003113

Reexamination

Applicant(s)/Patent Under

SEKIGUCHI ET AL.

Examiner

Hung, Yubin

Art Unit 2624

## **SEARCHED**

Class	Class Subclass		Examiner
382	166,190,199,232,233,243,254,263,264,266,275	12/23/08	YH
348	384.1	12/23/08	YH
358	426.01	12/23/08	YH
375	240	12/23/08	YH
708	203	12/23/08	YH

## **SEARCH NOTES**

Search Notes	Date	Examiner
EAST text search (USPGPUB, USPAT, EPO, JPO, DERWENT, IBM-TDB)	12/23/08	YH
Inventor search (EAST/eDAN)	12/23/08	YH
Assignee search (EAST/eDAN)	12/23/08	YH
ACM	2/25/07	YH
SPIE	2/25/07	YH
IEEE Xplore	2/25/07	YH

## INTERFERENCE SEARCH

Class	Subclass	Date	Examiner
382	199,233,243	12/23/08	YH
708	203	12/23/08	YH

/YUBIN HUNG/ Primary Examiner.Art Unit 2624

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